

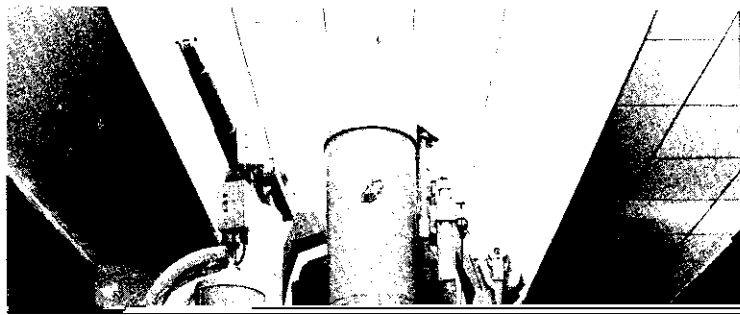
Application of 400 kV High Resolution Analytical Electron

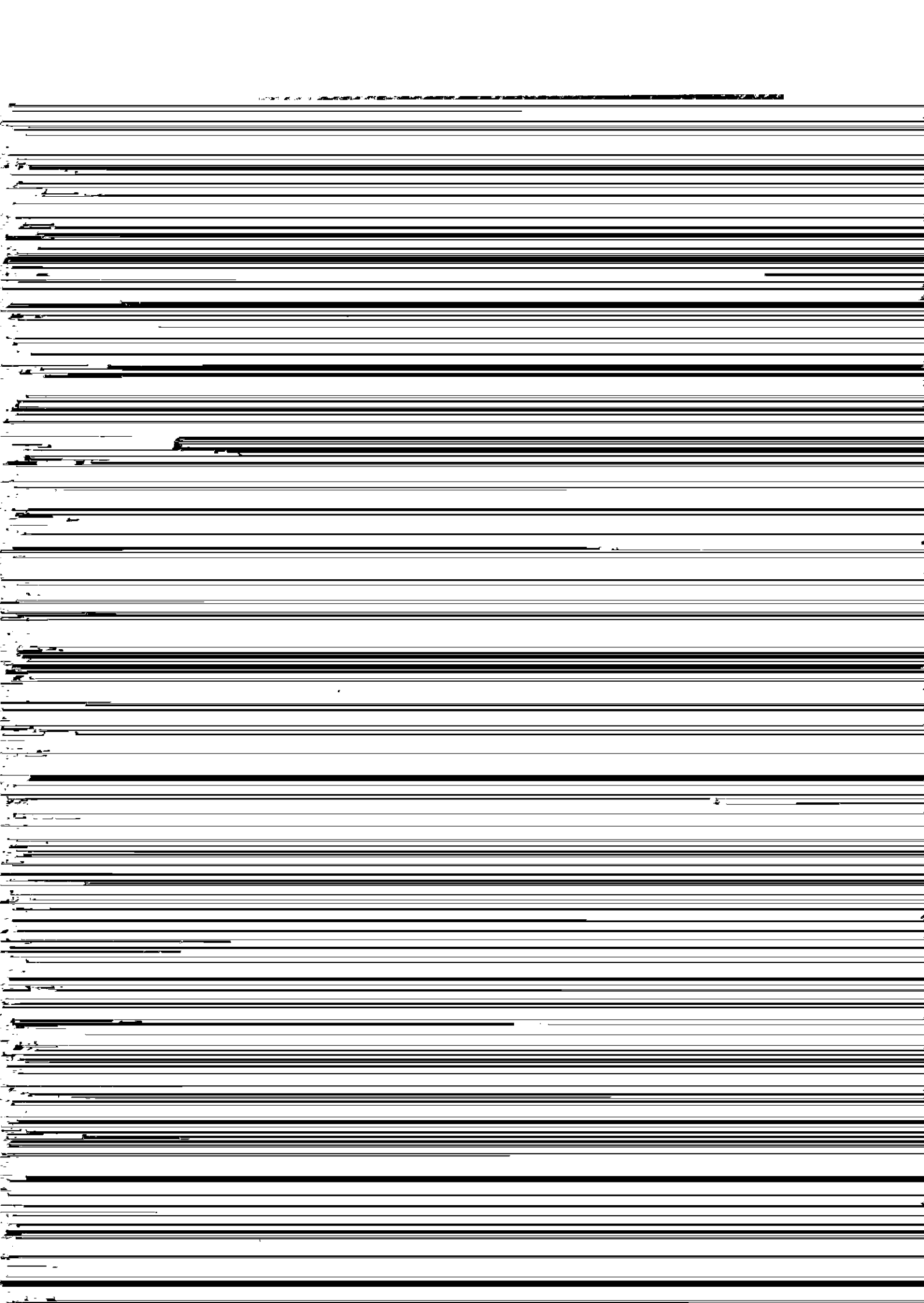
Microscope to Materials Research*

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1 Introduction

ing power (0.19 nm) and the other with emphasis on
analytical function (resolving power: 0.25 nm). The sub-





ment analysis with ITW-FDX from the position of the

Phase _____